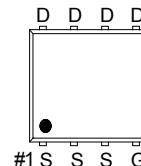
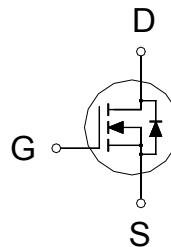


NIKO-SEM
**N-Channel Enhancement Mode
Field Effect Transistor**
**PE552BA
PDFN 3x3P
Halogen-Free & Lead-Free**
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D^3
20V	5mΩ	47A


G : GATE
D : DRAIN
S : SOURCE
ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	20	V
Gate-Source Voltage	V_{GS}	± 8	V
Continuous Drain Current ³	I_D	47	A
		30	
		15	
		12	
Pulsed Drain Current ¹	I_{DM}	70	
Avalanche Current	I_{AS}	38.6	
Avalanche Energy	E_{AS}	74.6	mJ
Power Dissipation	P_D	19	W
		7	
		2	
		1.3	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		60	°C / W
Junction-to-Case	$R_{\theta JC}$		6.5	

¹Pulse width limited by maximum junction temperature.²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.³Package limitation current is 22A**ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	20			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.4	0.7	0.9	

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Gate-Body Leakage	I_{GSS}	$V_{DS} = 0V, V_{GS} = \pm 8V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 16V, V_{GS} = 0V$			1	μA
		$V_{DS} = 10V, V_{GS} = 0V, T_J = 55^\circ C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 5A$		4.1	5	$m\Omega$
		$V_{GS} = 2.5V, I_D = 5A$		4.7	5.7	
		$V_{GS} = 1.8V, I_D = 5A$		6	8.2	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 5A$		70		s
DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 10V, f = 1MHz$		4407		pF
Output Capacitance	C_{oss}			469		
Reverse Transfer Capacitance	C_{rss}			381		
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		0.7		Ω
Total Gate Charge ²	Q_g	$V_{GS} = 4.5V, V_{DS} = 10V, I_D = 5A$		49		nC
Gate-Source Charge ²	Q_{gs}			6		
Gate-Drain Charge ²	Q_{gd}			13		
Turn-On Delay Time ²	$t_{d(on)}$	$V_{DD} = 4.5V$ $I_D \geq 5A, V_{GEN} = 10V, R_G = 6\Omega$		20		nS
Rise Time ²	t_r			25		
Turn-Off Delay Time ²	$t_{d(off)}$			180		
Fall Time ²	t_f			85		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)						
Continuous Current ³	I_S				14	A
Forward Voltage ¹	V_{SD}	$I_F = 5A, V_{GS} = 0V$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 5A, dI_F/dt = 100A/\mu S$		24		nS
Reverse Recovery Charge	Q_{rr}			12		nC

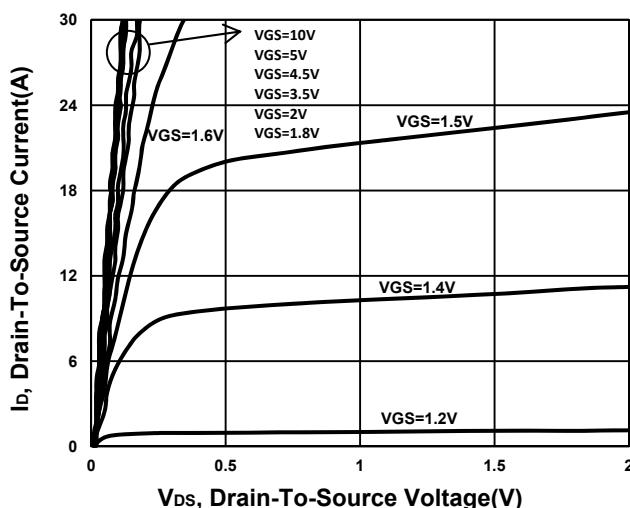
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.²Independent of operating temperature.

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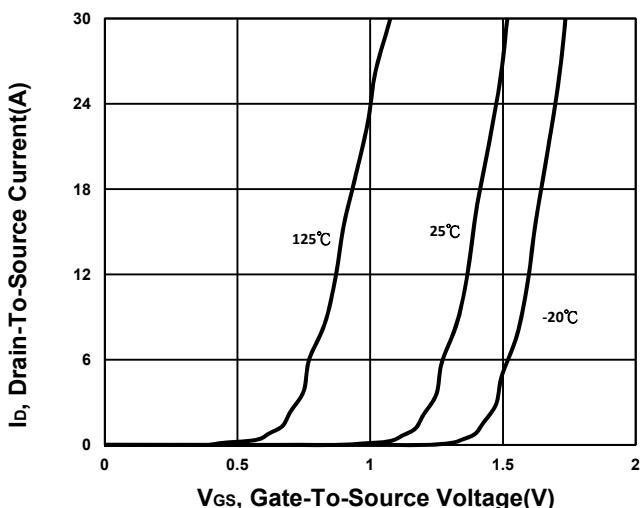
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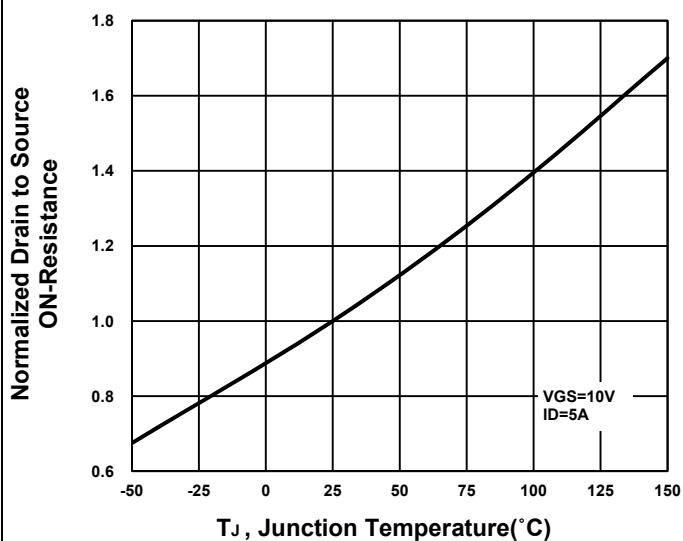
Output Characteristics



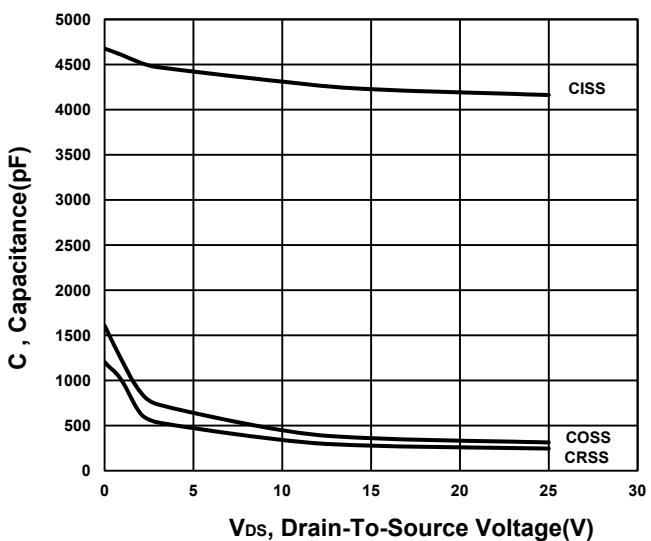
Transfer Characteristics



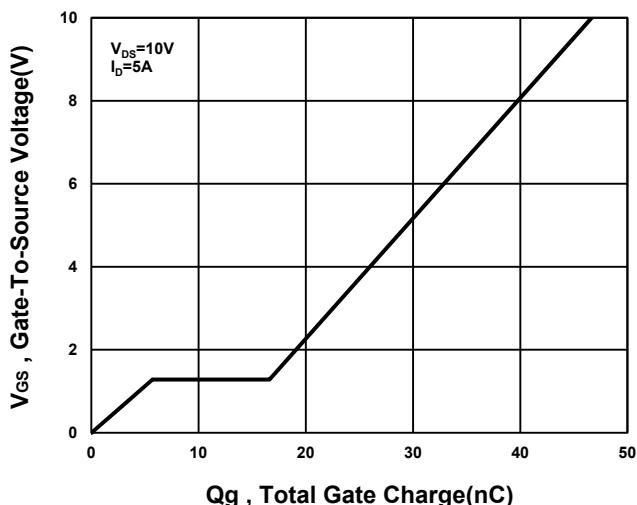
On-Resistance VS Temperature



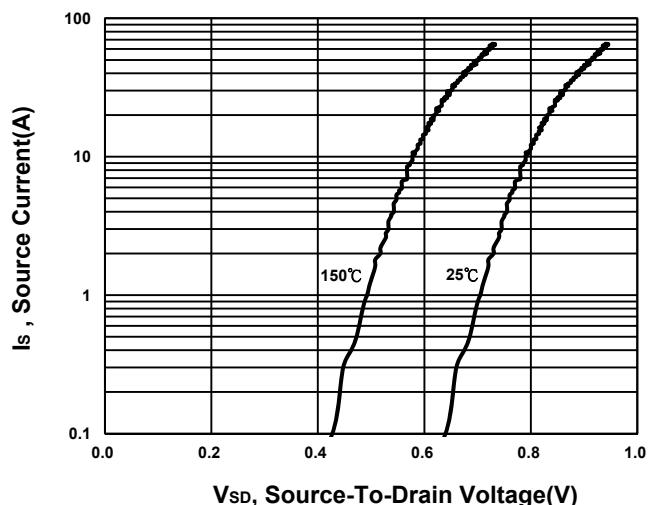
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



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